

INA280-Q1 AEC-Q100、2.7V~120V、1.1MHz、高精度電流センス・アンプ、小型 (SC-70) パッケージ

1 特長

- 車載アプリケーション用に AEC-Q100 認定取得済み:
 - 温度グレード 1: -40°C ~ +125°C、T_A
- 機能安全対応
 - 機能安全システムの設計に役立つ資料を利用可能
- 広い同相電圧範囲:
 - 動作電圧: 2.7V ~ 120V
 - 残存電圧: -20V ~ +122V
- 非常に優れた CMRR
 - 120dB (DC、最小値)
 - 85dB (AC、50kHz)
- 精度
 - ゲイン:
 - ゲイン誤差: ±0.5% (最大値)
 - ゲイン・ドリフト: ±20ppm/°C (最大値)
 - オフセット:
 - オフセット電圧: ±150μV (最大値)
 - オフセット・ドリフト: ±1μV/°C (最大値)
- 利用可能なゲイン:
 - INA280A1-Q1: 20V/V
 - INA280A2-Q1: 50V/V
 - INA280A3-Q1: 100V/V
 - INA280A4-Q1: 200V/V
 - INA280A5-Q1: 500V/V
- 広い帯域幅: 1.1MHz
- スルーレート: 2V/μs
- 静止電流: 370μA

2 アプリケーション

- 半導体 LiDAR
- 車載用 HVAC コンプレッサ・モジュール
- 車載ヒーター・モジュール
- 車載パーキング・ヒーター・モジュール
- 車載用ポンプ

3 概要

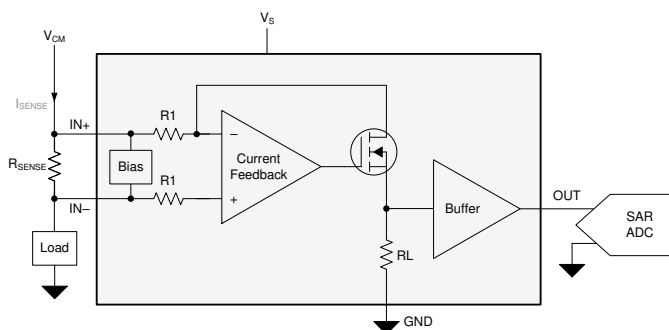
INA280-Q1 は、2.7V ~ 120V の広い同相範囲にわたってシャント抵抗の電圧降下を測定できる電流センス・アンプです。この製品は、PCB フットプリントがわずか 2.0mm × 2.1mm のスペース効率の高い SC-70 パッケージに搭載されています。±150μV 以下の極めて低いオフセット電圧、±0.5% 以下の小さいゲイン誤差、140dB (標準値) の高い DC CMRR により、高精度の電流測定を実現します。INA280-Q1 は DC 電流測定だけでなく、高速アプリケーション (たとえば高速過電流保護など) にも対応するように設計されており、1.1 MHz の広い帯域幅 (ゲイン 20V/V 時) と 85dB の AC CMRR (50kHz 時) を特長としています。

INA280-Q1 は 2.7V ~ 20V の単一電源で動作し、消費電流は 370μA (標準値) です。INA280-Q1 については、次のゲインを持つ 5 種類のバリエーションを提供しています。20V/V、50V/V、100V/V、200V/V、500V/V。INA280-Q1 はオフセットとドリフトが小さいため、拡張動作温度範囲の -40°C ~ +125°C にわたって、高精度の電流センシングが可能です。

製品情報

部品番号	パッケージ ⁽¹⁾	本体サイズ (公称)
INA280-Q1	SC-70 (5)	2.00mm × 1.25mm

(1) 利用可能なすべてのパッケージについては、このデータシートの末尾にあるパッケージ・オプションについての付録を参照してください。



代表的なアプリケーション



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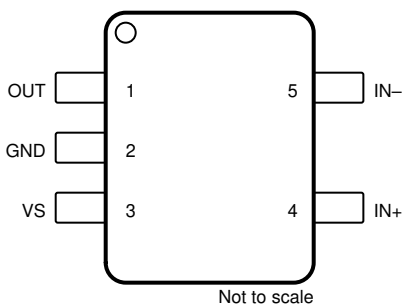
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4 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

DATE	REVISION	NOTES
November 2020	*	Initial Release

5 Pin Configuration and Functions



✎ 5-1. DCK Package 5-Pin SC-70 Top View

表 5-1. Pin Functions

PIN		TYPE	DESCRIPTION
NAME	NO.		
GND	2	Ground	Ground
IN–	5	Input	Connect to load side of shunt resistor
IN+	4	Input	Connect to supply side of shunt resistor
OUT	1	Output	Output voltage
VS	3	Power	Power supply

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V_S	Supply Voltage	−0.3	22	V
Analog Inputs, V_{IN+} , V_{IN-} ⁽²⁾	Differential (V_{IN+}) − (V_{IN-})	−30	30	V
	Common - mode	−20	122	V
Output		GND − 0.3	$V_S + 0.3$	V
T_A	Operating Temperature	−55	150	°C
T_J	Junction temperature		150	°C
T_{stg}	Storage temperature	−65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) V_{IN+} and V_{IN-} are the voltages at the V_{IN+} and V_{IN-} pins, respectively.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per AEC Q100-002, all pins ⁽¹⁾ HBM ESD Classification Level 2	±2000	V
		Charged device model (CDM), per AEC Q100-011, all pins CDM ESD Classification Level C6	±1000	

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V_{CM}	Common-mode input range ⁽¹⁾	V_S	48	120	V
V_S	Operating supply range	2.7	5	20	V
T_A	Ambient temperature	−40		125	°C

- (1) Common-mode voltage can go below V_S under certain conditions. See [7-1](#) for additional information on operating range.

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		INA280-Q1	UNIT
		DCK (SC-70)	
		5 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	191.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	144.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	69.2	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	46.2	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	69.0	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

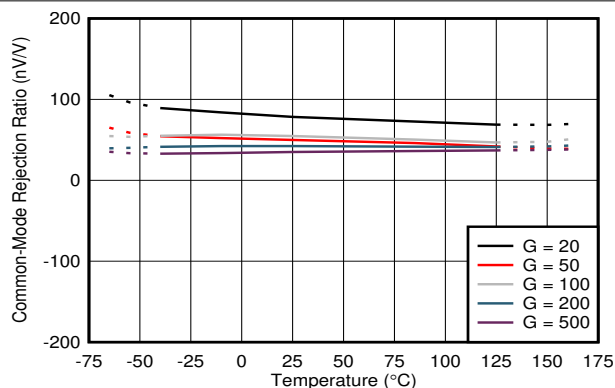
6.5 Electrical Characteristics

at $T_A = 25\text{ }^{\circ}\text{C}$, $V_S = 5\text{ V}$, $V_{\text{SENSE}} = V_{\text{IN}+} - V_{\text{IN}-} = 0.5\text{ V} / \text{Gain}$, $V_{\text{CM}} = V_{\text{IN}-} = 48\text{ V}$ (unless otherwise noted)

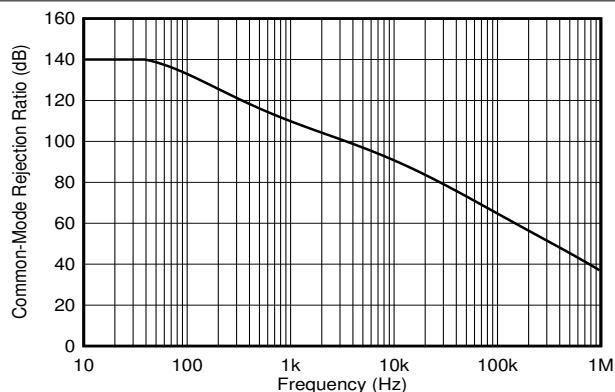
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
INPUT						
CMRR	Common-mode rejection ratio	$V_{\text{CM}} = 2.7\text{ V to }120\text{ V}$, $T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$	120	140		dB
		$f = 50\text{ kHz}$		85		
V_{OS}	Offset voltage, input referred			15	± 150	μV
$\text{d}V_{\text{OS}}/\text{d}T$	Offset voltage drift	$T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$			1	$\mu\text{V}/^{\circ}\text{C}$
PSRR	Power supply rejection ratio, input referred	$V_{\text{S}} = 2.7\text{ V to }20\text{ V}$, $T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$		1	± 10	$\mu\text{V/V}$
I_{B}	Input bias current	$I_{\text{B+}}$, $V_{\text{SENSE}} = 0\text{ mV}$	10	20	30	μA
		$I_{\text{B-}}$, $V_{\text{SENSE}} = 0\text{ mV}$	10	20	30	
OUTPUT						
G	Gain	A1 devices		20		V/V
		A2 devices		50		
		A3 devices		100		
		A4 devices		200		
		A5 devices		500		
	Gain error	$\text{GND} + 50\text{ mV} \leq V_{\text{OUT}} \leq V_{\text{S}} - 200\text{ mV}$		0.1	± 0.5	%
	Gain error drift	$T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$		2.5	20	$\text{ppm}/^{\circ}\text{C}$
	Nonlinearity error			0.01		%
	Maximum capacitive load	No sustained oscillations, no isolation resistor		500		pF
VOLTAGE OUTPUT						
	Swing to V_{S} power supply rail	$R_{\text{LOAD}} = 10\text{ k}\Omega$, $T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$		$V_{\text{S}} - 0.07$	$V_{\text{S}} - 0.2$	V
	Swing to ground	$R_{\text{LOAD}} = 10\text{ k}\Omega$, $V_{\text{SENSE}} = 0\text{ V}$, $T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$		0.005	0.025	V
FREQUENCY RESPONSE						
BW	Bandwidth	A1 devices, $C_{\text{LOAD}} = 5\text{ pF}$, $V_{\text{SENSE}} = 200\text{ mV}$		1100		kHz
		A2 devices, $C_{\text{LOAD}} = 5\text{ pF}$, $V_{\text{SENSE}} = 80\text{ mV}$		1100		
		A3 devices, $C_{\text{LOAD}} = 5\text{ pF}$, $V_{\text{SENSE}} = 40\text{ mV}$		900		
		A4 devices, $C_{\text{LOAD}} = 5\text{ pF}$, $V_{\text{SENSE}} = 20\text{ mV}$		850		
		A5 devices, $C_{\text{LOAD}} = 5\text{ pF}$, $V_{\text{SENSE}} = 8\text{ mV}$		800		
SR	Slew rate			2		V/ μs
	Settling time	$V_{\text{OUT}} = 4\text{ V} \pm 0.1\text{ V}$ step, output settles to 0.5%		9		μs
		$V_{\text{OUT}} = 4\text{ V} \pm 0.1\text{ V}$ step, output settles to 1%		5		
NOISE						
V_{eN}	Voltage noise density			50		nV/ $\sqrt{\text{Hz}}$
POWER SUPPLY						
V_{S}	Supply voltage	$T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$	2.7		20	V
I_{Q}	Quiescent current			370	500	μA
		$T_{\text{A}} = -40\text{ }^{\circ}\text{C to }+125\text{ }^{\circ}\text{C}$			600	

6.6 Typical Characteristics

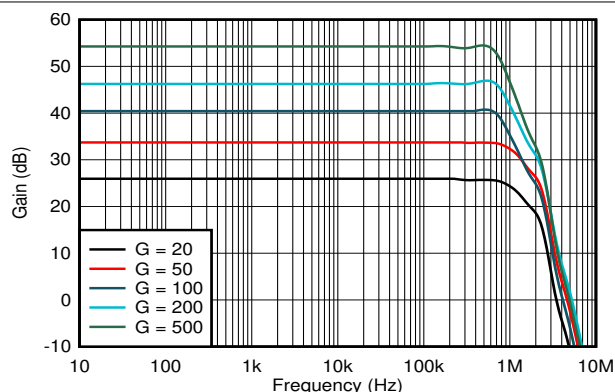
All specifications at $T_A = 25\text{ }^{\circ}\text{C}$, $V_S = 5\text{ V}$, $V_{\text{SENSE}} = V_{\text{IN}+} - V_{\text{IN}-} = 0.5\text{ V} / \text{Gain}$, and $V_{\text{CM}} = V_{\text{IN}-} = 48\text{ V}$, unless otherwise noted.



6-1. Common-Mode Rejection Ratio vs Temperature

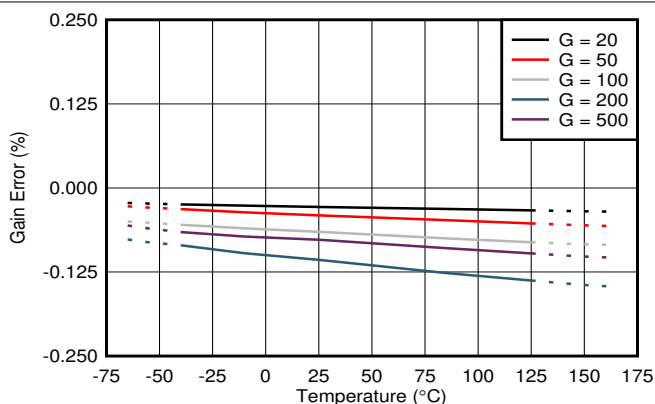


6-2. Common-Mode Rejection Ratio vs Frequency

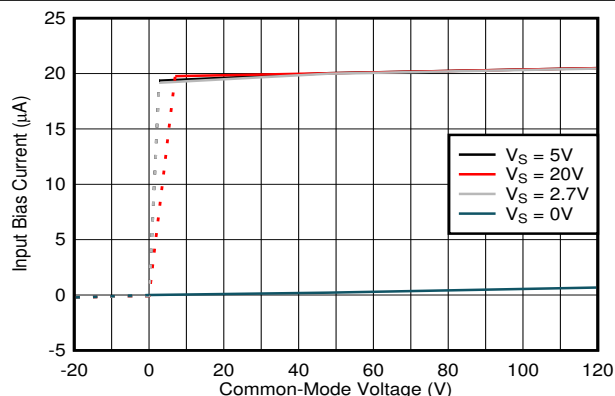


$V_{\text{SENSE}} = 4\text{ V} / \text{Gain}$

6-3. Gain vs Frequency

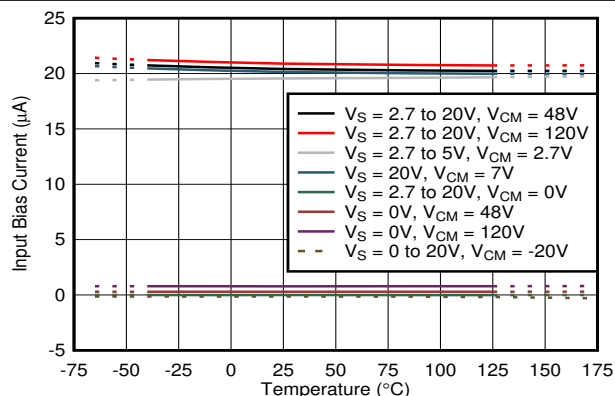


6-4. Gain Error vs Temperature



$V_{\text{SENSE}} = 0\text{ V}$

6-5. Input Bias Current vs Common-Mode Voltage



6-6. Input Bias Current vs Temperature

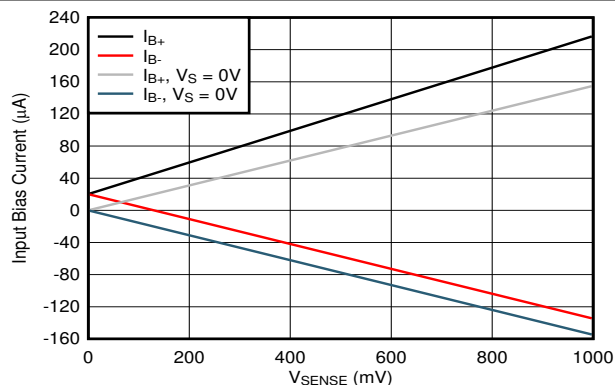


Figure 6-7. Input Bias Current vs V_{SENSE} , A1 Devices

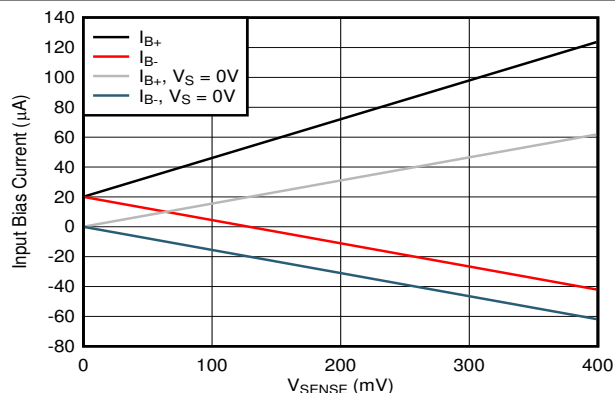


Figure 6-8. Input Bias Current vs V_{SENSE} , A2 and A3 Devices

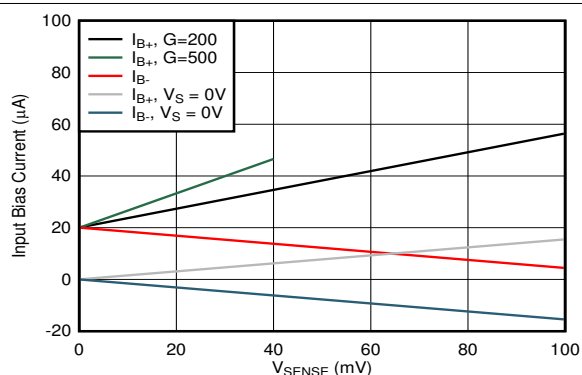


Figure 6-9. Input Bias Current vs V_{SENSE} , A4 and A5 Devices

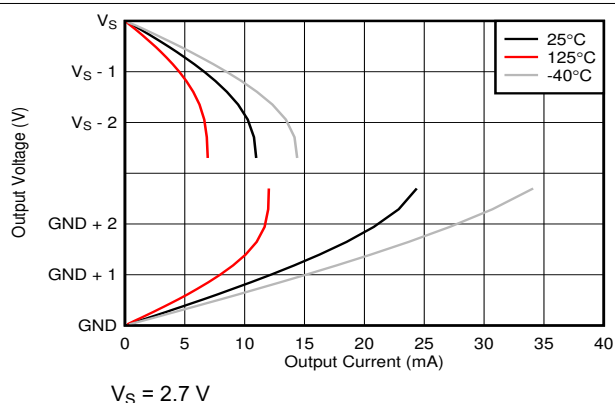


Figure 6-10. Output Voltage vs Output Current

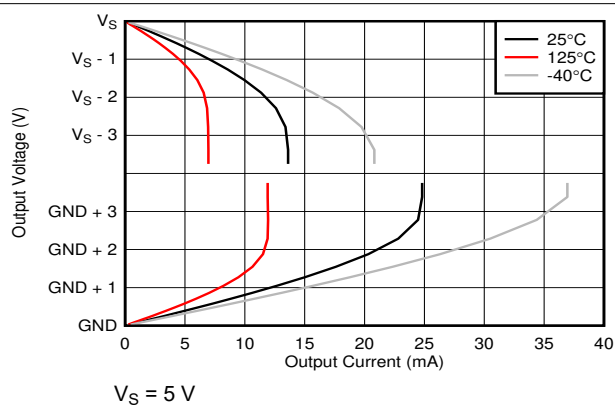


Figure 6-11. Output Voltage vs Output Current

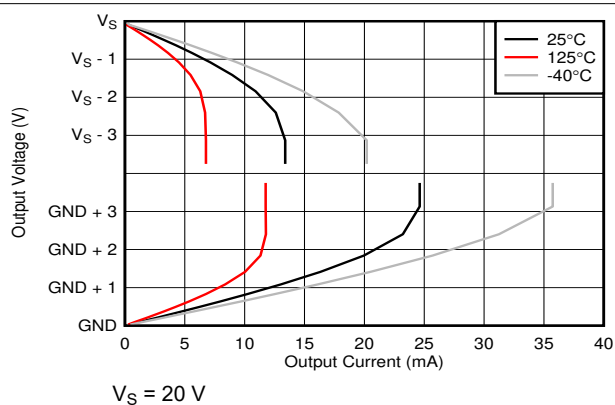
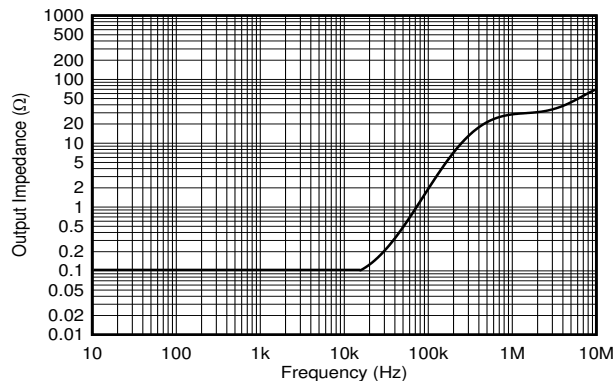
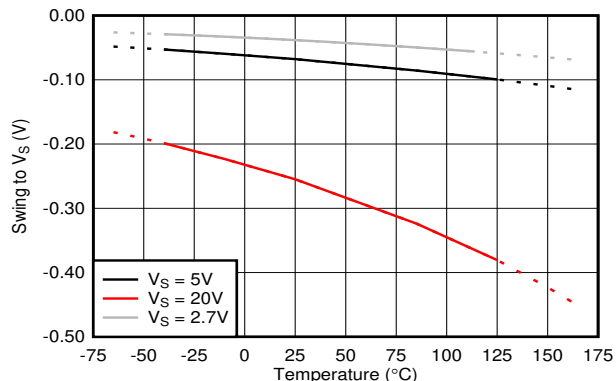
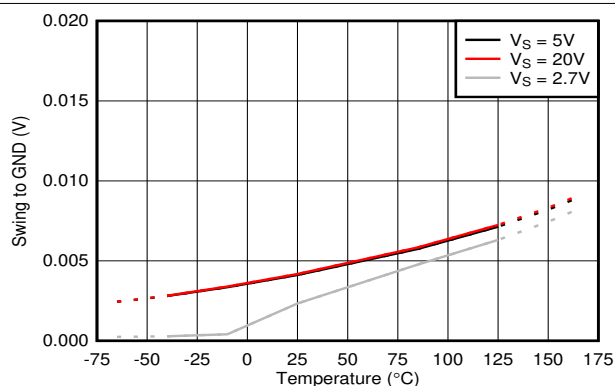
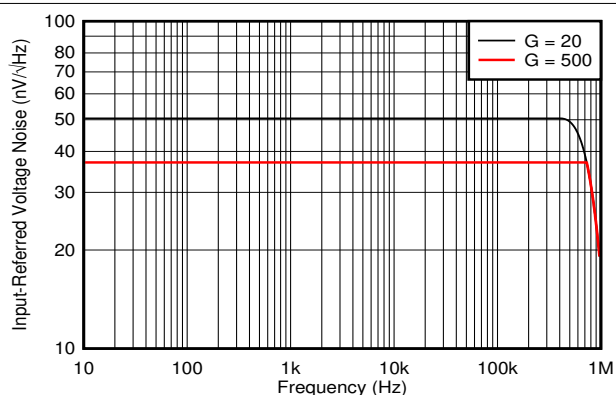
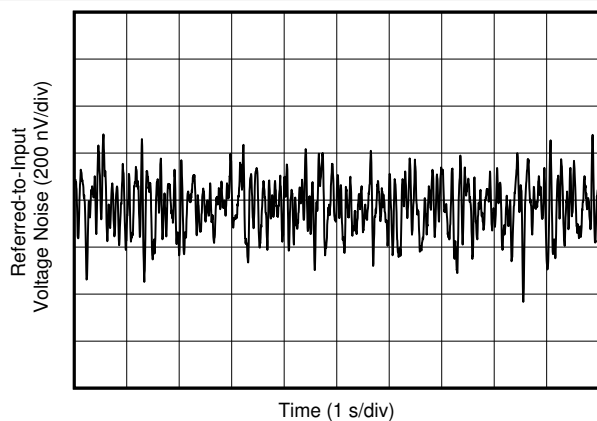
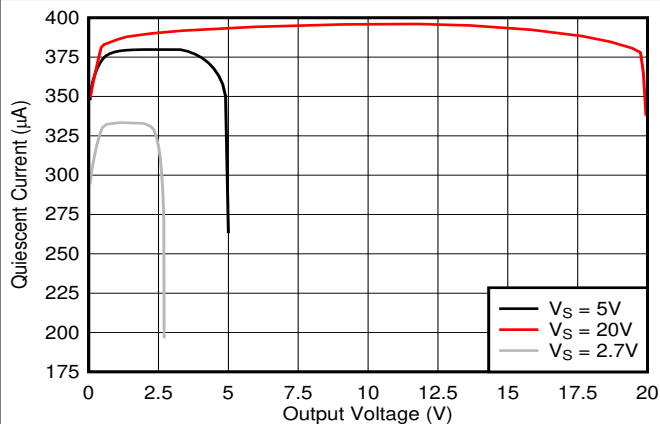
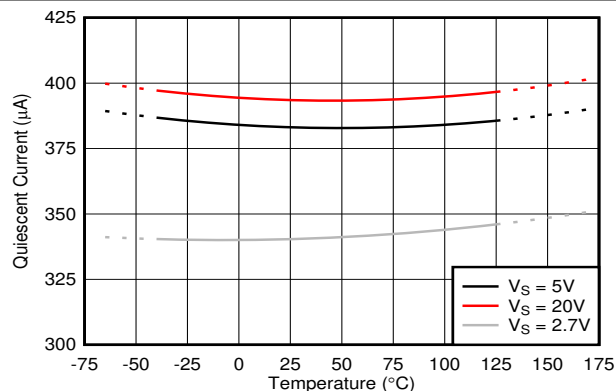
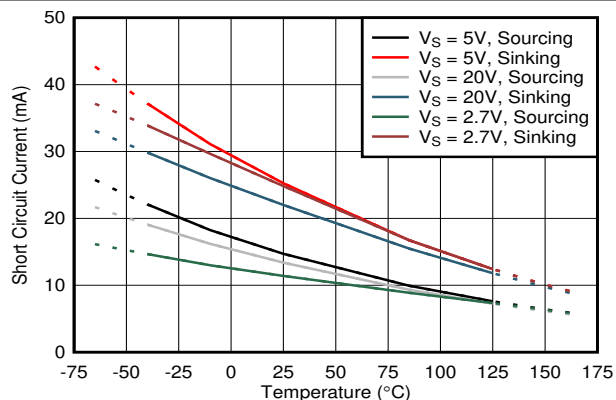


Figure 6-12. Output Voltage vs Output Current

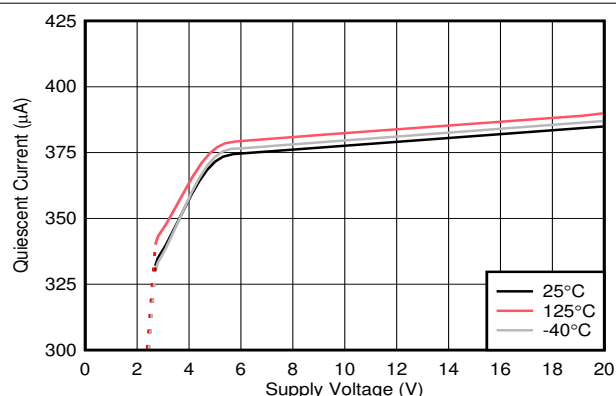

Figure 6-13. Output Impedance vs Frequency

 $R_L = 10\text{ k}\Omega$
Figure 6-14. Swing to Supply vs Temperature

 $R_L = 10\text{ k}\Omega$
Figure 6-15. Swing to GND vs Temperature

Figure 6-16. Input Referred Noise vs Frequency

Figure 6-17. Input Referred Noise

Figure 6-18. Quiescent Current vs Output Voltage



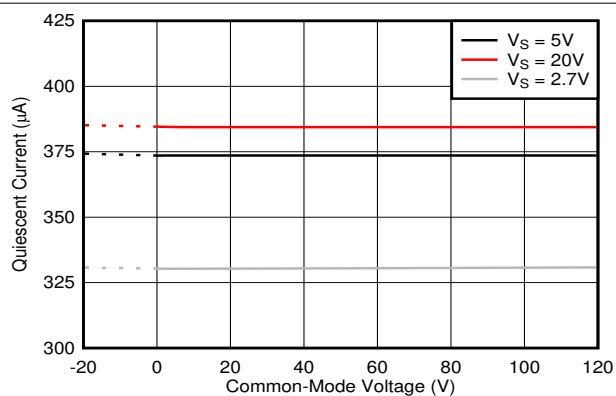
6-19. Quiescent Current vs Temperature



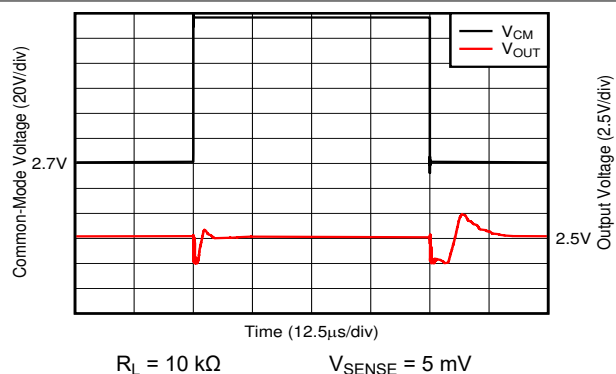
6-20. Short-Circuit Current vs Temperature



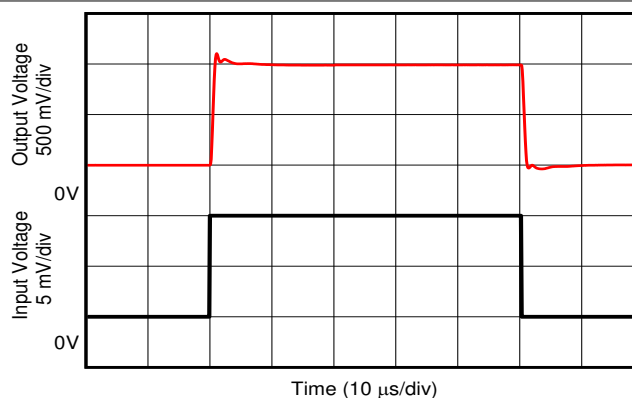
6-21. Quiescent Current vs Supply Voltage



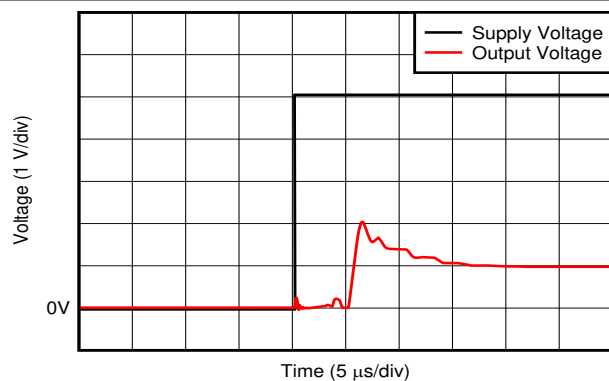
6-22. Quiescent Current vs Common-Mode Voltage



6-23. Common-Mode Voltage Fast Transient Pulse, A5 Devices

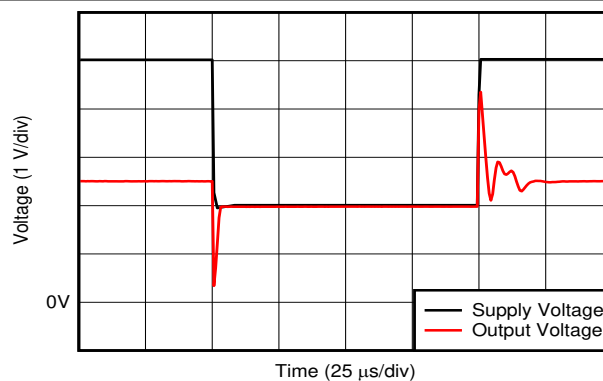


6-24. Step Response, A3 Devices



$V_{\text{SENSE}} = 0 \text{ mV}$

6-25. Start-Up Response



$V_{\text{SENSE}} = 5 \text{ mV}$

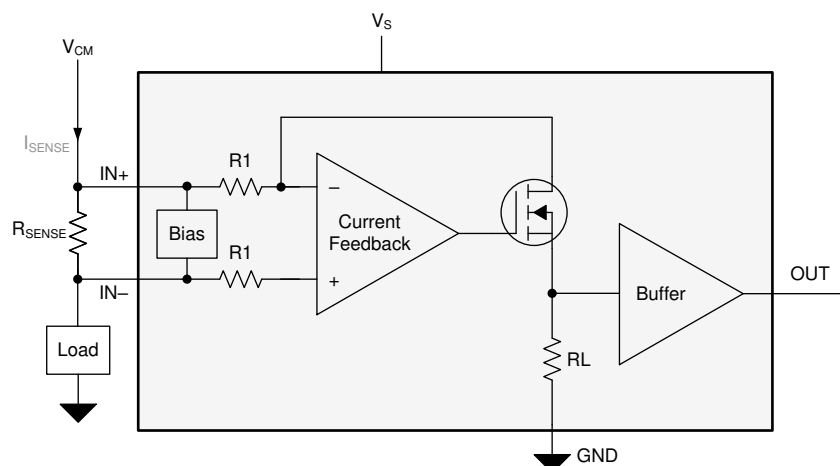
6-26. Supply Transient Response, A5 Devices

7 Detailed Description

7.1 Overview

The INA280-Q1 is a high-side only current-sense amplifier that offers a wide common-mode range, excellent common-mode rejection ratio (CMRR), high bandwidth, and fast slew rate. Different gain versions are available to optimize the output dynamic range based on the application. The INA280-Q1 is designed using a transconductance architecture with a current-feedback amplifier that enables low bias currents of 20 μA and a common-mode voltage of 120 V.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Amplifier Input Common-Mode Range

The INA280-Q1 supports large input common-mode voltages from 2.7 V to 120 V and features a high DC CMRR of 140 dB (typical) and a 85-dB AC CMRR at 50 kHz. The minimum common-mode voltage is restricted by the supply voltage as shown in [Figure 7-1](#). The topology of the internal amplifiers INA280-Q1 restricts operation to high-side, current-sensing applications.

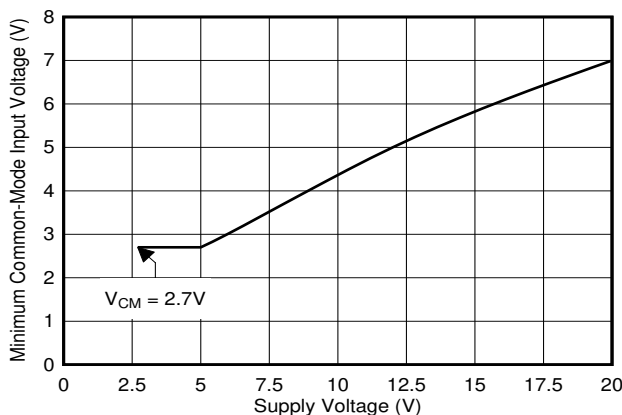


Figure 7-1. Minimum Common-Mode Voltage vs Supply

7.3.1.1 Input-Signal Bandwidth

The INA280-Q1 –3-dB bandwidth is gain dependent with several gain options of 20 V/V, 50 V/V, 100 V/V, 200 V/V, and 500 V/V as shown in [Figure 6-2](#). The unique multistage design enables the amplifier to achieve high bandwidth at all gains. This high bandwidth provides the throughput and fast response that is required for the rapid detection and processing of overcurrent events.

The bandwidth of the device also depends on the applied V_{SENSE} voltage. [Figure 7-2](#) shows the bandwidth performance profile of the device over frequency as output voltage increases for each gain variation. As shown in [Figure 7-2](#), the device exhibits the highest bandwidth with higher V_{SENSE} voltages, and the bandwidth is higher with lower device gain options. Individual requirements determine the acceptable limits of error for high-frequency, current-sensing applications. Testing and evaluation in the end application or circuit is required to determine the acceptance criteria and validate whether or not the performance levels meet the system specifications.

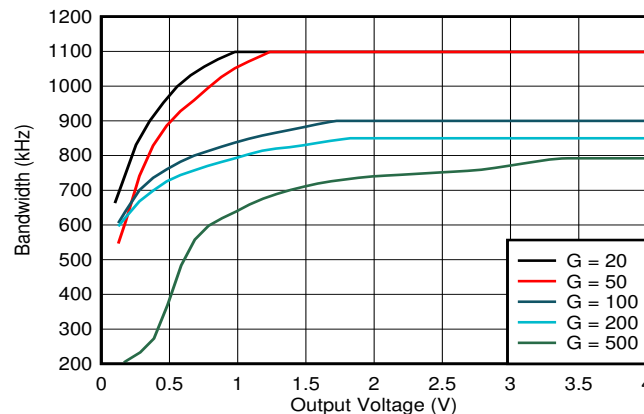


Figure 7-2. Bandwidth vs Output Voltage

7.3.1.2 Low Input Bias Current

The INA280-Q1 input bias current draws 20 μ A (typical) even with common-mode voltages as high as 120 V. This enables precision current sensing in applications where the sensed current is small or applications that require lower input leakage current.

7.3.1.3 Multiple Fixed Gain Outputs

The INA280-Q1 gain error is < 0.5% at room temperature for all gain options, with a maximum drift of 20ppm/°C over the full temperature range of –40 °C to +125 °C. The INA280-Q1 is available in multiple gain options of 20 V/V, 50 V/V, 100 V/V, 200 V/V, and 500 V/V, which the system designer should select based on their desired signal-to-noise ratio and other system requirements.

The INA280-Q1 closed-loop gain is set by a precision, low-drift internal resistor network. Even though the ratio of these resistors are well matched, the absolute value of these resistors may vary significantly. TI does not recommend adding additional resistance around the INA280-Q1 to change the effective gain because of this variation, however. The typical values of the gain resistors are described in [Table 7-1](#).

Table 7-1. Fixed Gain Resistor

GAIN	R1	RL
20 (V/V)	25 k Ω	500 k Ω
50 (V/V)	10 k Ω	500 k Ω
100 (V/V)	10 k Ω	1000 k Ω
200 (V/V)	5 k Ω	1000 k Ω
500 (V/V)	2 k Ω	1000 k Ω

7.3.1.4 Wide Supply Range

The INA280-Q1 operates with a wide supply range from a 2.7 V to 20 V. The output stage supports a full-scale output voltage range of up to V_S . Wide output range can enable very-wide dynamic range current measurements. For a gain of 20 V/V, the maximum differential input acceptable is 1 V.

7.4 Device Functional Modes

7.4.1 Unidirectional Operation

The INA280-Q1 measures the differential voltage developed by current flowing through a resistor that is commonly referred to as a current-sensing resistor or a current-shunt resistor. The INA280-Q1 operates in unidirectional mode only, meaning it only senses current sourced from a power supply to a system load as shown in [Figure 7-3](#).

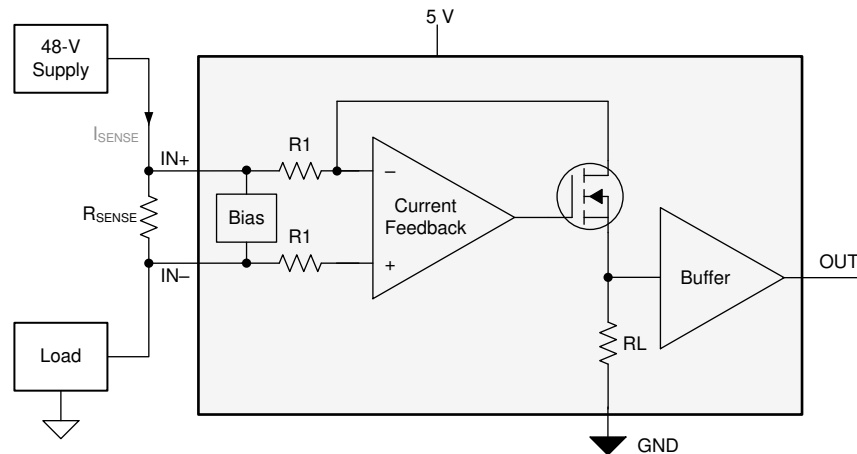


Figure 7-3. Unidirectional Application

The linear range of the output stage is limited to how close the output voltage can approach ground under zero-input conditions. The zero current output voltage of the INA280-Q1 is very small, with a maximum of GND + 25 mV. Make sure to apply a sense voltage of (25 mV / Gain) or greater to keep the INA280-Q1 output in the linear region of operation.

7.4.2 High Signal Throughput

With a bandwidth of 1.1 MHz at a gain of 20 V/V and a slew rate of 2 V/ μ s, the INA280-Q1 is specifically designed for detecting and protecting applications from fast inrush currents. As shown in [Table 7-2](#), the INA280-Q1 responds in less than 2 μ s for a system measuring a 75-A threshold on a 2-m Ω shunt.

Table 7-2. Response Time

PARAMETER		EQUATION	INA280-Q1 AT $V_S = 5$ V
G	Gain		20 V/V
I_{MAX}	Maximum current		100 A
$I_{Threshold}$	Threshold current		75 A
R_{SENSE}	Current sense resistor value		2 m Ω
V_{OUT_MAX}	Output voltage at maximum current	$V_{OUT} = I_{MAX} \times R_{SENSE} \times G$	4 V
V_{OUT_THR}	Output voltage at threshold current	$V_{OUT_THR} = I_{THR} \times R_{SENSE} \times G$	3 V
SR	Slew rate		2 V/ μ s
	Output response time	$T_{response} = V_{OUT_THR} / SR$	< 2 μ s

8 Application and Implementation

Note

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8.1 Application Information

The INA280-Q1 amplifies the voltage developed across a current-sensing resistor as current flows through the resistor to the load. The wide input common-mode voltage range and high common-mode rejection of the INA280-Q1 allows use over a wide range of voltage rails while still maintaining an accurate current measurement.

8.1.1 R_{SENSE} and Device Gain Selection

The accuracy of any current-sense amplifier is maximized by choosing the current-sense resistor to be as large as possible. A large sense resistor maximizes the differential input signal for a given amount of current flow and reduces the error contribution of the offset voltage. However, there are practical limits as to how large the current-sense resistor can be in a given application because of the resistor size and maximum allowable power dissipation. 式 1 gives the maximum value for the current-sense resistor for a given power dissipation budget:

$$R_{\text{SENSE}} < \frac{PD_{\text{MAX}}}{I_{\text{MAX}}^2} \quad (1)$$

where:

- PD_{MAX} is the maximum allowable power dissipation in R_{SENSE} .
- I_{MAX} is the maximum current that will flow through R_{SENSE} .

An additional limitation on the size of the current-sense resistor and device gain is due to the power-supply voltage, V_S , and device swing-to-rail limitations. To make sure that the current-sense signal is properly passed to the output, both positive and negative output swing limitations must be examined. 式 2 provides the maximum values of R_{SENSE} and GAIN to keep the device from exceeding the positive swing limitation.

$$I_{\text{MAX}} \times R_{\text{SENSE}} \times \text{GAIN} < V_{\text{SP}} \quad (2)$$

where:

- I_{MAX} is the maximum current that will flow through R_{SENSE} .
- GAIN is the gain of the current-sense amplifier.
- V_{SP} is the positive output swing as specified in the data sheet.

To avoid positive output swing limitations when selecting the value of R_{SENSE} , there is always a trade-off between the value of the sense resistor and the gain of the device under consideration. If the sense resistor selected for the maximum power dissipation is too large, then it is possible to select a lower-gain device in order to avoid positive swing limitations.

The negative swing limitation places a limit on how small the sense resistor value can be for a given application. 式 3 provides the limit on the minimum value of the sense resistor.

$$I_{\text{MIN}} \times R_{\text{SENSE}} \times \text{GAIN} > V_{\text{SN}} \quad (3)$$

where:

- I_{MIN} is the minimum current that will flow through R_{SENSE} .
- GAIN is the gain of the current-sense amplifier.

- V_{SN} is the negative output swing of the device.

表 8-1 shows an example of the different results obtained from using five different gain versions of the INA280-Q1. From the table data, the highest gain device allows a smaller current-shunt resistor and decreased power dissipation in the element.

表 8-1. R_{SENSE} Selection and Power Dissipation

PARAMETER ⁽¹⁾		EQUATION	RESULTS AT $V_S = 5\text{ V}$				
			INA280A1Q	INA280A2Q	INA280A3Q	INA280A4Q	INA280A5Q
G	Gain		20 V/V	50 V/V	100 V/V	200 V/V	500 V/V
V_{SENSE}	Ideal differential input voltage (Ignores swing limitation and power supply variation.)	$V_{SENSE} = V_{OUT} / G$	250 mV	100 mV	50 mV	25 mV	10 mV
R_{SENSE}	Current sense resistor value	$R_{SENSE} = V_{SENSE} / I_{MAX}$	25 mΩ	10 mΩ	5 mΩ	2.5 mΩ	1 mΩ
P_{SENSE}	Current-sense resistor power dissipation	$R_{SENSE} \times I_{MAX}^2$	2.5 W	1 W	0.5W	0.25 W	0.1 W

(1) Design example with 10-A full-scale current with maximum output voltage set to 5 V.

8.1.2 Input Filtering

Note

Input filters are not required for accurate measurements using the INA280, and use of filters in this location is not recommended. If filter components are used on the input of the amplifier, follow the guidelines in this section to minimize the effects on performance.

Based strictly on user design requirements, external filtering of the current signal may be desired. The initial location that can be considered for the filter is at the output of the current-sense amplifier. Although placing the filter at the output satisfies the filtering requirements, this location changes the low output impedance measured by any circuitry connected to the output voltage pin. The other location for filter placement is at the current-sense amplifier input pins. This location also satisfies the filtering requirement, but the components must be carefully selected to minimally impact device performance. 图 8-1 shows a filter placed at the input pins.

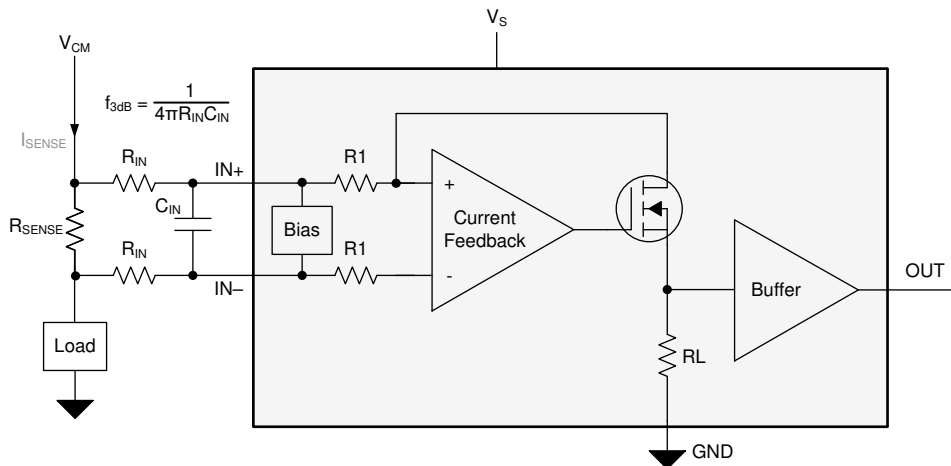


图 8-1. Filter at Input Pins

External series resistance provides a source of additional measurement error, so keep the value of these series resistors to 10 Ω or less to reduce loss of accuracy. The internal bias network shown in Figure 38 creates a mismatch in input bias currents (see 图 6-7, 图 6-8, and 图 6-9) when a differential voltage is applied between the input pins. If additional external series filter resistors are added to the circuit, a mismatch is created in the voltage drop across the filter resistors. This voltage is a differential error voltage in the shunt resistor voltage. In addition to the absolute resistor value, mismatch resulting from resistor tolerance can significantly impact the error because this value is calculated based on the actual measured resistance.

The measurement error expected from the additional external filter resistors can be calculated using 式 4, where the gain error factor is calculated using 式 5.

$$\text{Gain Error (\%)} = 100 \times (\text{Gain Error Factor} - 1) \quad (4)$$

The gain error factor, shown in 式 4, can be calculated to determine the gain error introduced by the additional external series resistance. 式 4 calculates the deviation of the shunt voltage, resulting from the attenuation and imbalance created by the added external filter resistance. 表 8-2 provides the gain error factor and gain error for several resistor values.

$$\text{Gain Error Factor} = \frac{R_B \times R_1}{(R_B \times R_1) + (R_B \times R_{IN}) + (2 \times R_{IN} \times R_1)} \quad (5)$$

Where:

- R_{IN} is the external filter resistance value.
- R_1 is the INA280 input resistance value specified in 表 7-1.
- R_B is the internal bias resistance, which is $6600 \, \Omega \pm 20\%$.

表 8-2. Example Gain Error Factor and Gain Error for 10- Ω External Filter Input Resistors

DEVICE (GAIN)	GAIN ERROR FACTOR	GAIN ERROR (%)
A1 devices (20)	0.99658	–0.34185
A2 devices (50)	0.99598	–0.40141
A3 devices (100)	0.99598	–0.40141
A4 devices (200)	0.99499	–0.50051
A5 devices (500)	0.99203	–0.79663

8.2 Typical Application

The INA280-Q1 is a unidirectional, current-sense amplifier capable of measuring currents through a resistive shunt with shunt common-mode voltages from 2.7 V to 120 V. The circuit configuration for monitoring current in a high-side pump or motor application is shown in 图 8-2.

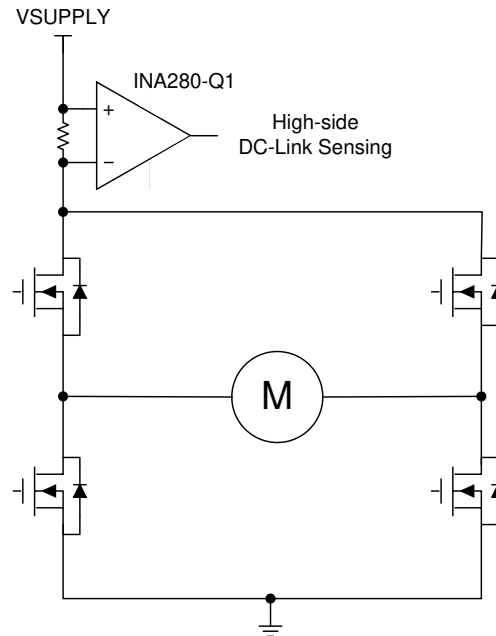


图 8-2. Current Sensing in a Automotive Pump Application

8.2.1 Design Requirements

V_{SUPPLY} is set to 5 V, and the common-mode voltage set to 48 V. 表 8-3 lists the design setup for this application.

表 8-3. Design Parameters

DESIGN PARAMETERS	EXAMPLE VALUE
INA280-Q1 supply voltage	5 V
High-side supply voltage	48 V
Maximum sense current (I_{MAX})	5 A
Gain option	50 V/V

8.2.2 Detailed Design Procedure

The maximum value of the current-sense resistor is calculated based choice of gain, value of the maximum current the be sensed (I_{MAX}), and the power-supply voltage (V_S). When operating at the maximum current, the output voltage must not exceed the positive output swing specification, V_{SP} . Under the given design parameters, 式 6 calculates the maximum value for R_{SENSE} as 19.2 mΩ.

$$R_{SENSE} < \frac{V_{SP}}{I_{MAX} \times GAIN} \quad (6)$$

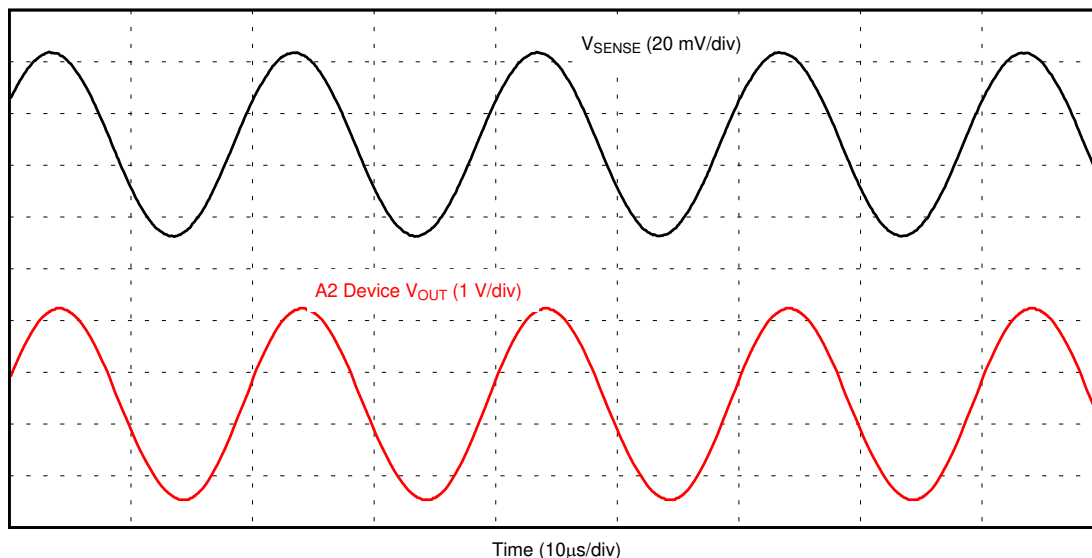
For this design example, a value of 15 mΩ is selected because, while the 15 mΩ is less than the maximum value calculated, 15 mΩ is still large enough to give adequate signal at the current-sense amplifier output.

8.2.2.1 Overload Recovery With Negative V_{SENSE}

The INA280 is a unidirectional current-sense amplifier that is meant to operate with a positive differential input voltage (V_{SENSE}). If negative V_{SENSE} is applied, the device is placed in an overload condition and requires time to recover once V_{SENSE} returns positive. The required overload recovery time increases with more negative V_{SENSE} .

8.2.3 Application Curve

图 8-3 shows the output response of the device to a high frequency sinusoidal current.



INA2

 **8-3. INA280 Output Response**

9 Power Supply Recommendations

The input circuitry of the INA280-Q1 device can accurately measure beyond the power-supply voltage. The power supply can be 20 V, whereas the load power-supply voltage at IN+ and IN– can go up to 120 V. The output voltage range of the OUT pin is limited by the voltage on the V_S pin and the device swing to supply specification.

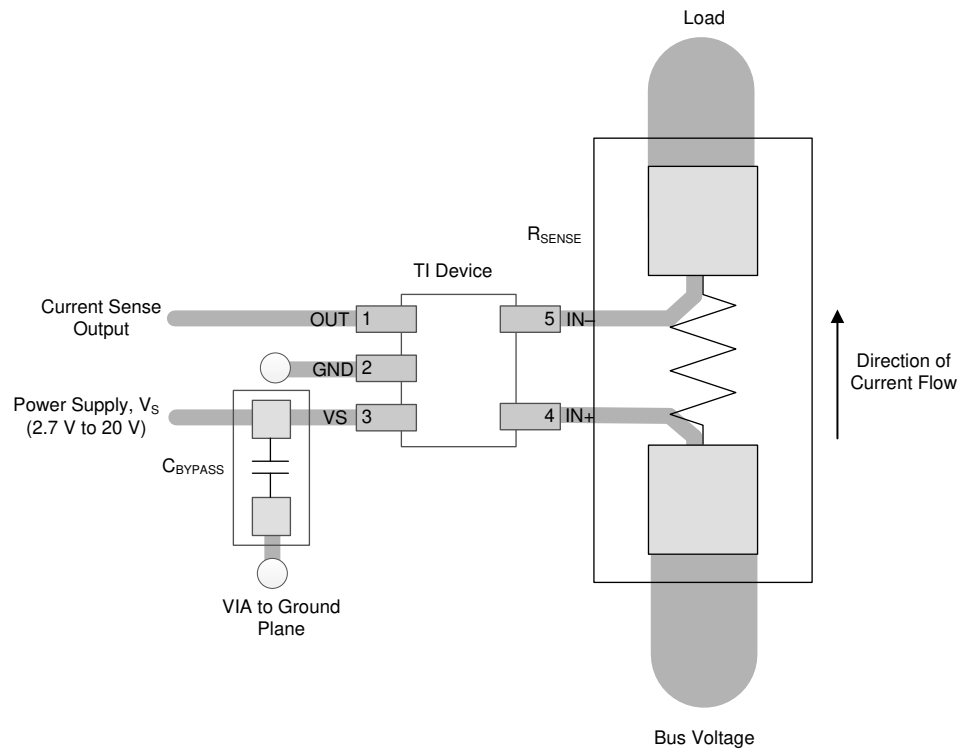
10 Layout

10.1 Layout Guidelines

TI always recommends to follow good layout practices:

- Connect the input pins to the sensing resistor using a Kelvin or 4-wire connection. This connection technique makes sure that only the current-sensing resistor impedance is detected between the input pins. Poor routing of the current-sensing resistor commonly results in additional resistance present between the input pins. Given the very low ohmic value of the current resistor, any additional high-current carrying impedance can cause significant measurement errors.
- Place the power-supply bypass capacitor as close to the device power supply and ground pins as possible. The recommended value of this bypass capacitor is 0.1 μ F. Additional decoupling capacitance can be added to compensate for noisy or high-impedance power supplies.
- When routing the connections from the current-sense resistor to the device, keep the trace lengths as short as possible.

10.2 Layout Example



10-1. Recommended Layout for INA280-Q1

11 Device and Documentation Support

11.1 Documentation Support

11.1.1 Related Documentation

For related documentation, see the following:

Texas Instruments, [INA280EVM User's Guide](#)

11.2 ドキュメントの更新通知を受け取る方法

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11.6 用語集

[TI 用語集](#) この用語集には、用語や略語の一覧および定義が記載されています。

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
INA280A1QDCKRQ1	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GT
INA280A1QDCKRQ1.B	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GT
INA280A2QDCKRQ1	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GU
INA280A2QDCKRQ1.B	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GU
INA280A3QDCKRQ1	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GV
INA280A3QDCKRQ1.B	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GV
INA280A4QDCKRQ1	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GW
INA280A4QDCKRQ1.B	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GW
INA280A5QDCKRQ1	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GX
INA280A5QDCKRQ1.B	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1GX

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF INA280-Q1 :

- Catalog : [INA280](#)

NOTE: Qualified Version Definitions:

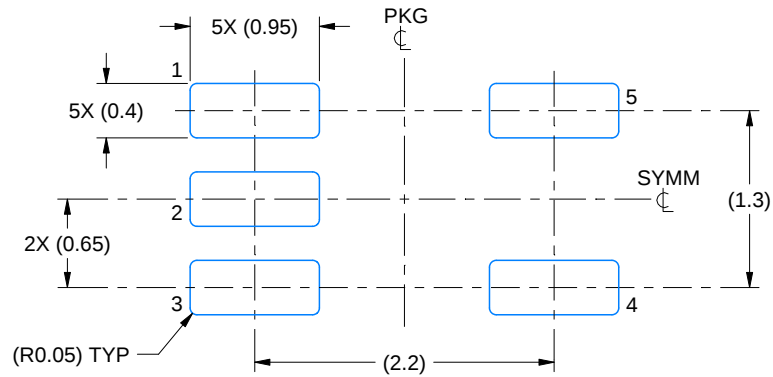
- Catalog - TI's standard catalog product



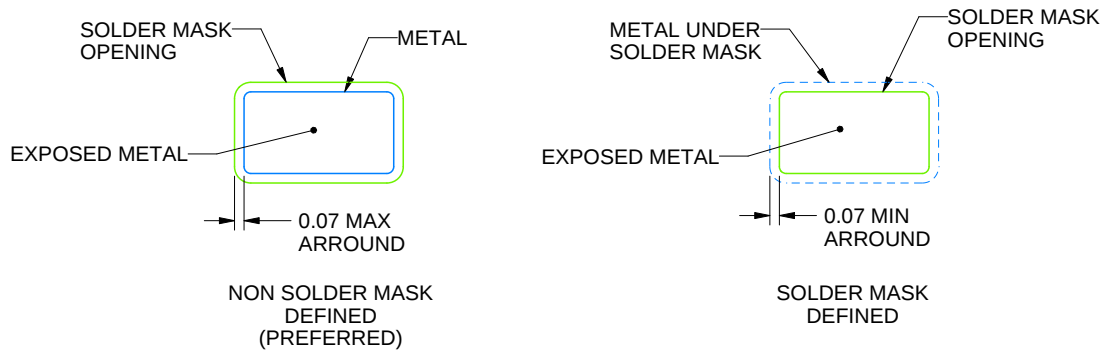
4214834/G 11/2024

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Reference JEDEC MO-203.
4. Support pin may differ or may not be present.
5. Lead width does not comply with JEDEC.
6. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25mm per side



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:18X



SOLDER MASK DETAILS

4214834/G 11/2024

NOTES: (continued)

7. Publication IPC-7351 may have alternate designs.
8. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
 BASED ON 0.125 THICK STENCIL
 SCALE:18X

4214834/G 11/2024

NOTES: (continued)

9. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
10. Board assembly site may have different recommendations for stencil design.

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